

	Hit s	Search Text	DBs
32	22	((selective\$5 or response or signal\$4 or (defect near9 portion)) same (sensor or detect\$4 or interferomet\$4 or SEM) same (mitigat\$4 or reduc\$4 or decreas\$4 or monitor\$4 or reflow or (thermal near5 reflow) or RELACS or SAFIER or post\$4heat\$4 or heat\$4) same (pattern or ((resist or photoresist or photosensitive)))) and ((trim\$6 or etch\$5 or CMP or PEB or post\$5bak or bak\$5) same (asymmetr\$5 or deviat\$5 or varia\$5 or difference) same (pattern or profile or feature or CD or LER) sam e (photoresist or resist) same correct\$5)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB

	Hit s	Search Text	DBs
33	38	((selective\$5 or response or signal\$4 or (defect near9 portion)) same (sensor or detect\$4 or interferomet\$4 or SEM) same (mitigat\$4 o r reduc\$4 or decreas\$4 or monitor\$4 or reflow or (thermal near5 reflow) or RELACS or SAFIER or post\$4heat\$4 or heat\$4) same (pattern or ((resist or photoresist or photosensitive)))) and ((trim\$6 or etch\$5 or CMP or PEB or post\$5bak or bak\$5 or correct\$4) same (asymmetr\$5 or deviat\$5 or varia\$5 or difference) same (pattern or profile or feature or CD or LER) same (photoresist or resist) same correct\$5) and gate	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB